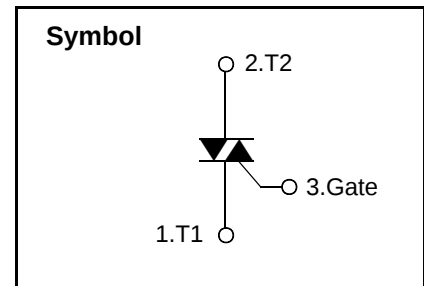
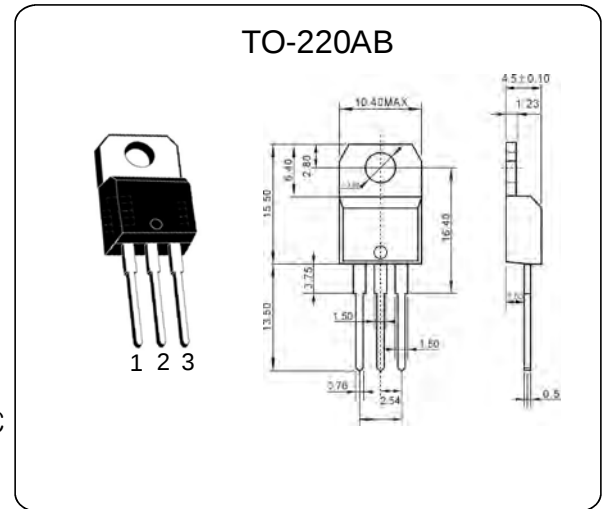


Bi-Directional Triode Thyristor

Designed for high performance full-wave ac control applications where high noise immunity and high commutating di/dt are required.

Features

- Blocking Voltage to 800 V
- On- State Current Rating of 16A RMS at 80 °C
- Uniform Gate Trigger Currents in Three Quadrants
- High Immunity to dV/dt- 1500V/us minimum at 125 °C
- Minimizes Snubber Networks for Protection
- Industry Standard TO- 220AB Package
- High Commutating dI/dt- 4.0A/ms minimum at 125 °C
- Internally Isolated (2500VRMS)
- These are Pb- Free Devices



Absolute Maximum Ratings

Symbol	Parameter			Value	Unit
$I_{T(RMS)}$	RMS on-state current(full sine wave)	TO-220AB	$T_C=100^{\circ}C$	16	A
		TO-220AB Ins.	$T_C=85^{\circ}C$		
I_{TSM}	Non repetitive surge peak on-state current(full cycle, T_j initial= $25^{\circ}C$)	F=50Hz	t=20ms	160	A
		F=60Hz	t=16.7ms	168	
I^2t	I^2t Value for fusing	tp=10ms		144	A^2s
DI/DT	Critical rate of rise of on-state current $I_G=2X_{IGT, tr \leq 100ns}$	F=120Hz	$T_j=125^{\circ}C$	50	A/us
VDSM/V RSM	Non repetitive surge peak off-state voltage	tp=10ms	$T_j=25^{\circ}C$	Vdrm / vrrm + 100V	V
IGM	Peak gate current	tp=20us	$T_j=125^{\circ}C$	4	A
$P_{G(AV)}$	Average gate power dissipation		$T_j=125^{\circ}C$	1	W
T_{stg}	Storage junction temperature range			-40 to +150	$^{\circ}C$
T_j	Operating junction temperature range			-40 to +125	

Electrical Characteristics (Tj=25°C, unless otherwise specified)

Snubberless™ and Logic Level(3 quadrants)

Symbol	Test conditions	Quadrant	BTA16		Unit
I _{GT} (1)	V _D =12V R _L =33Ω	I - II - III	MAX	50	mA
V _{GT}		I - II - III	MAX	1.3	V
V _{GD}	V _D =V _{DRM} R _L =3.3KΩTj=125°C	I - II - III	MIN	0.2	V
I _H (2)	IT=500mA		MAX	50	mA
I _L	I _G =1.2I _{GT}	I - III	MAX	70	mA
		II		80	
Dv / Dt(2)	V _D =67%V _{DRM} Gate open Tj=125°C		MIN	1000	V/us
(DI/dt)c(2)	(Dv/dt)c=0.1 V/us Tj=125°C		MIN	-	A/ms
	(Dv/dt)c=10V/us Tj=125°C			-	
	Without snubber Tj=125°C			14	

Standard (4 Quadrants)

Symbol	Test conditions	Quadrant	BTA16		Unit
IGT(1)	V _D =12V R _L =33Ω	I - II - III	MAX	50	mA
VGT		IV		100	
VGD	V _D =V _{DRM} R _L =3.3KΩTj=125°C	ALL	MIN	0.2	V
I _H (2)	IT=500mA		MAX	50	mA
I _L	I _G =1.2I _{GT}	I - III- IV	MAX	60	mA
		II		120	
(DI/dt)(2)	V _D =67%V _{DRM} Gate open Tj=125°C		MIN	400	V/us
(DI/dt)c(2)	(Dv/dt)c=7 A/ms Tj=125°C		MIN	10	V/us

Static Characteristics

Symbol	Test conditions			Value	Unit
V _{TM} (2)	ITM=22A tp=380us	TJ=25°C	MAX	1.55	V
V _{to} (2)	Threshold voltage	TJ=125°C	MAX	0.85	V
R _d (2)	Dynamic resistance	TJ=125°C	MAX	25	mΩ
I _{DRM}	V _{DRM} =V _{R_{RM}}	TJ=25°C	MAX	5	uA
I _{R_{RM}}		TJ=125°C		2	mA
V _{DRM} /V _{R_{RM}}	Voltage	TJ=25°C	MIN	600 and 800	V

Note 1: minimum IGT is guaranteed at 5% of IGT max

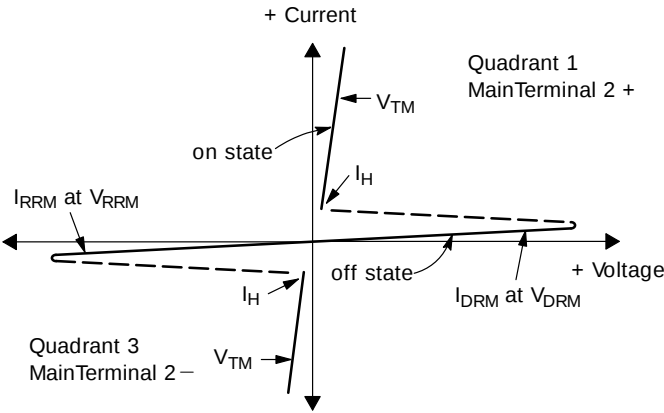
Note 2: for both polarities of A2 referenced to A1

Thermal Resistances

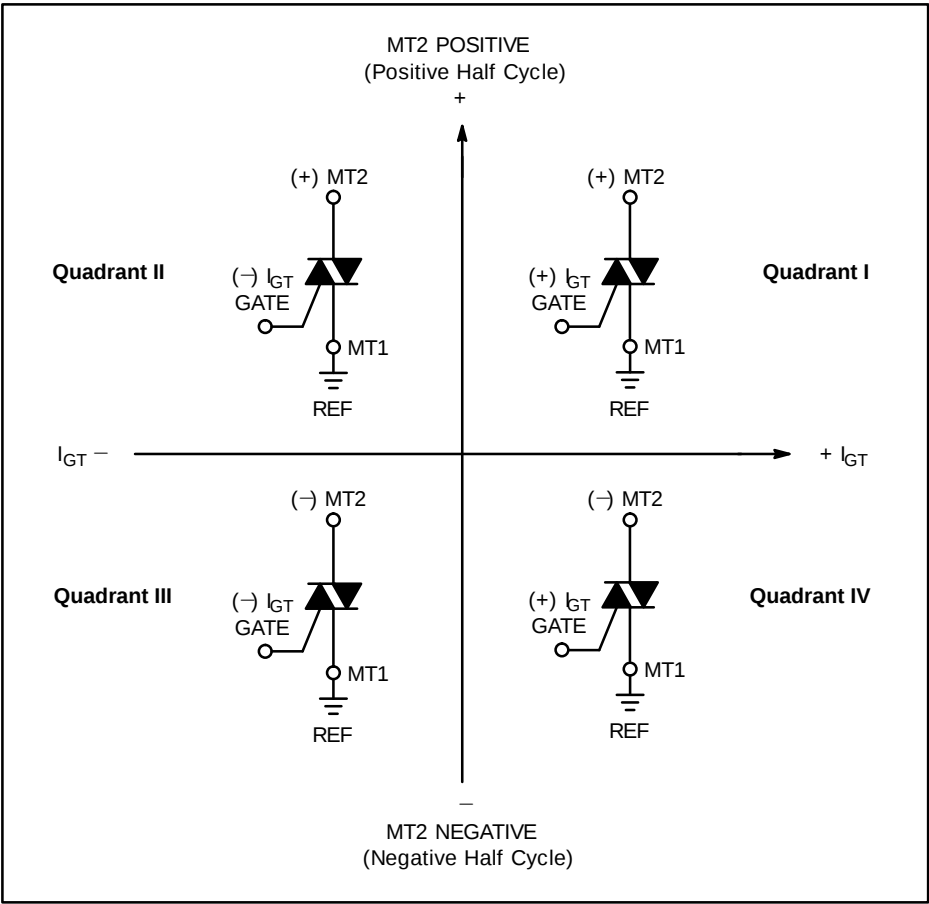
Symbol	Parameter		Value	Unit
R _{th(j-c)}	Junction to case(AC)	TO-220AB	1.2	°C/W
		TO-220AB(Insulated)	2.1	
R _{th(j-a)}	Junction to ambient	TO-220AB/ TO-220AB(Insulated)	60	°C/W

Voltage Current Characteristic of Triacs (Bidirectional Device)

Symbol	Parameter
V_{DRM}	Peak Repetitive Forward Off State Voltage
I_{DRM}	Peak Forward Blocking Current
V_{RRM}	Peak Repetitive Reverse Off State Voltage
I_{RRM}	Peak Reverse Blocking Current
V_{TM}	Maximum On State Voltage
I_H	Holding Current



Quadrant Definitions for a Triac



All polarities are referenced to MT1.
With in-phase signals (using standard AC lines) quadrants I and III are used.

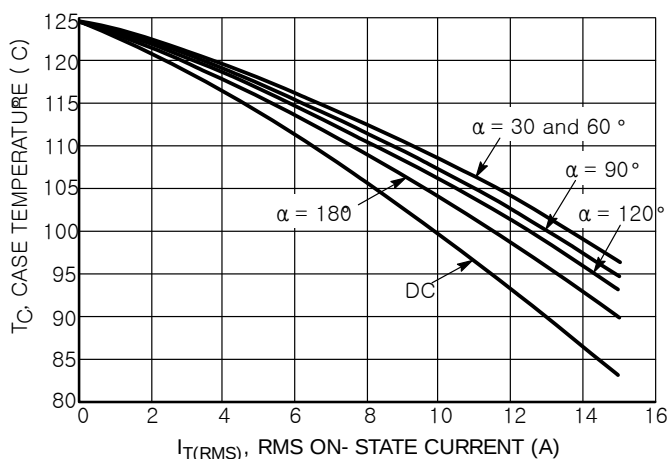


Figure 1. RMS Current Derating

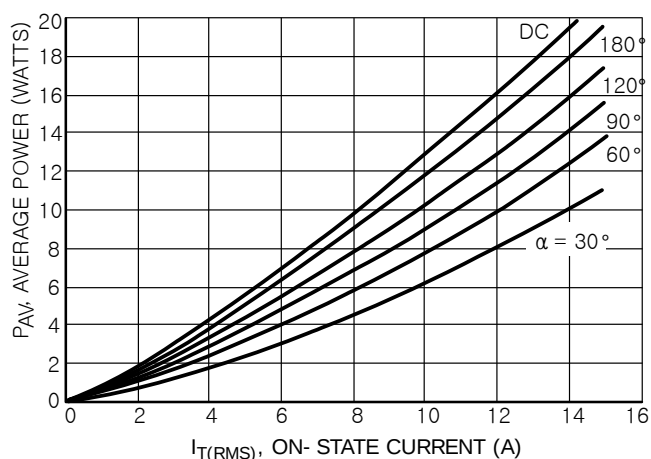


Figure 2. On- State Power Dissipation

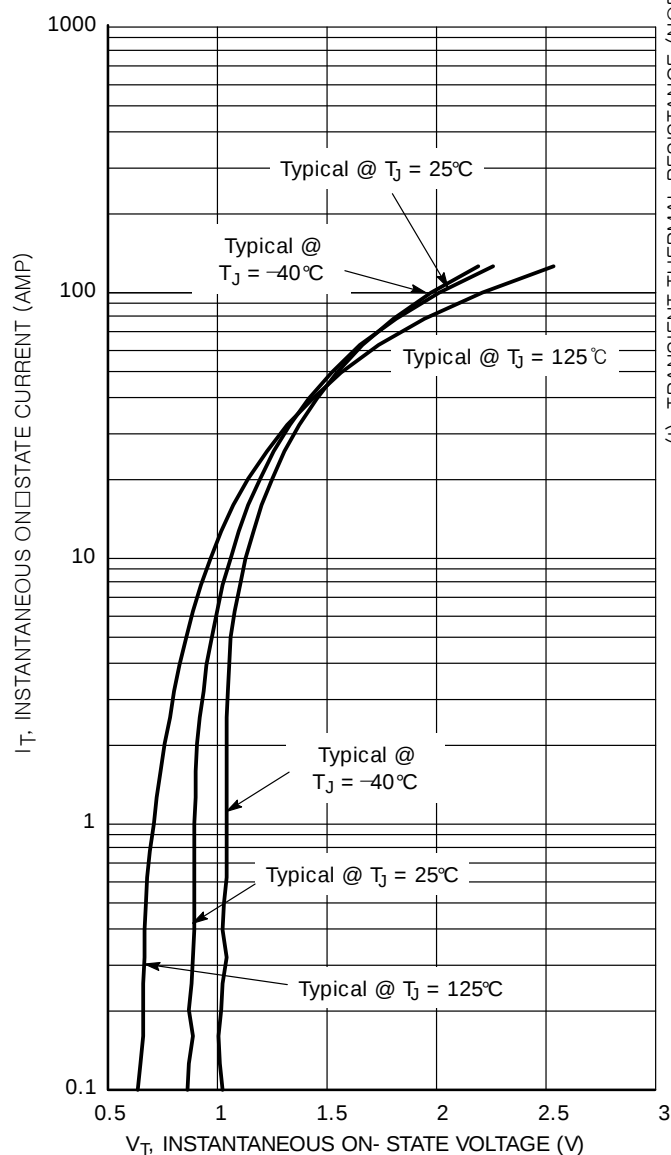


Figure 3. On- State Characteristics

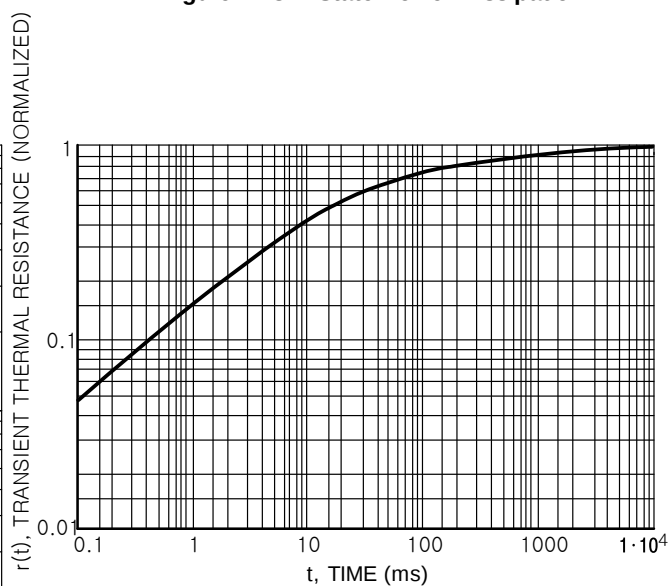


Figure 4. Thermal Response

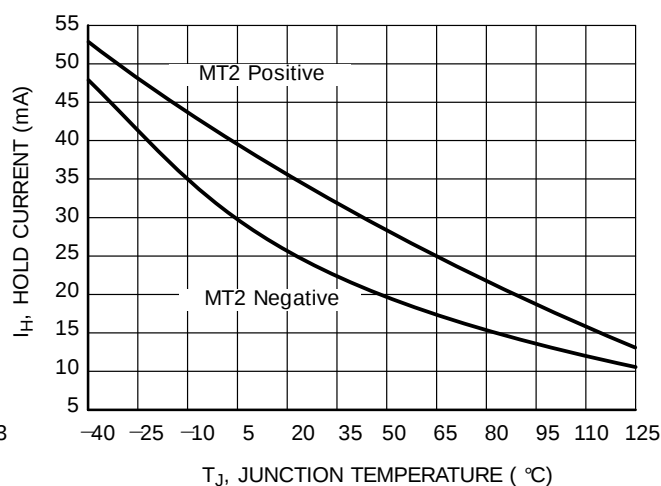


Figure 5. Hold Current Variation

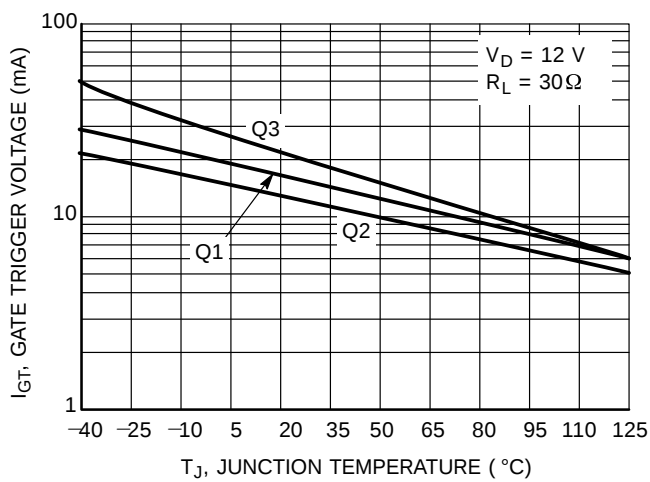


Figure 6. Gate Trigger Current Variation

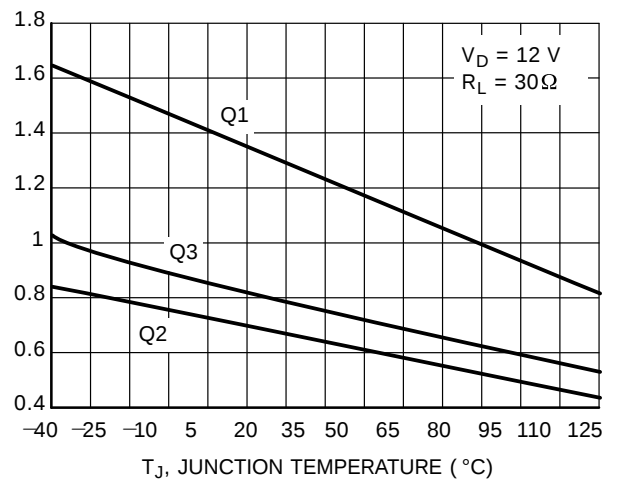


Figure 7. Gate Trigger Voltage Variation

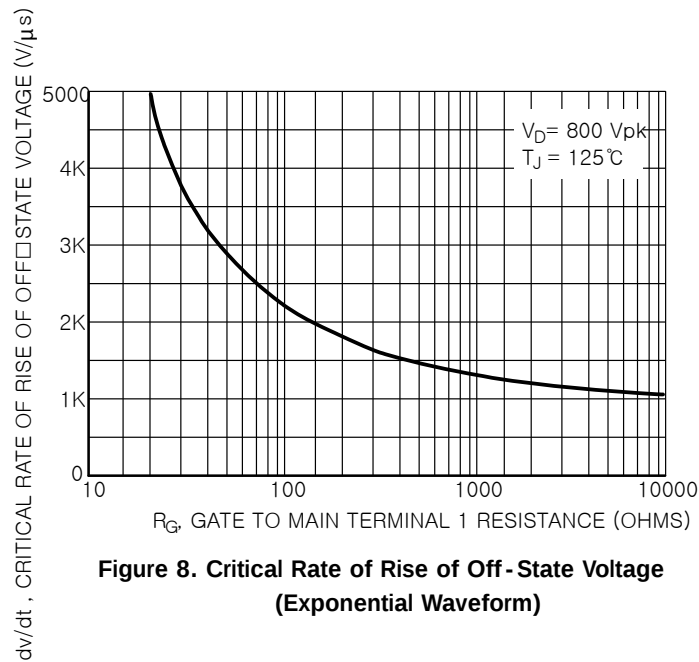
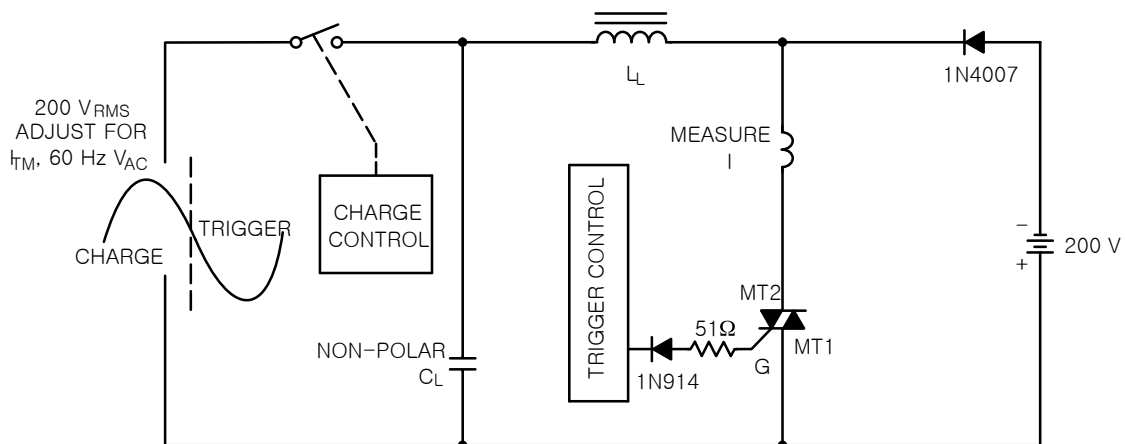


Figure 8. Critical Rate of Rise of Off-State Voltage (Exponential Waveform)



Note: Component values are for verification of rated $(di/dt)_c$. See AN1048 for additional information.

Figure 9. Simplified Test Circuit to Measure the Critical Rate of Rise of Commutating Current $(di/dt)_c$